

**POWER MOSFET  
THRU-HOLE (Low-Ohmic TO-254AA)**

**800V, N-CHANNEL**

**Product Summary**

Part Number	RDS(on)	I <sub>D</sub>
IRF3CMS17N80	0.34Ω	15A



**Description**

The MOSFET uses Infineon 800V C3 CoolMOS™ advanced technology to deliver high performance with low RDS(on) and fast switching in a low ohmic hermetic package. The 800V C3 CoolMOS™ technology uses proven Super Junction design and is implemented with ease of use in mind.

**Features**

- New Revolutionary High Voltage Technology
- Extreme dv/dt Rated
- High Peak Current Capability
- Ultra Low Gate Charge
- Ultra Low Effective Capacitance
- Ceramic Eyelets
- Electrically Isolated
- Light Weight
- ESD Rating: Class 3A per MIL-STD-750, Method 1020

**Absolute Maximum Ratings**

Symbol	Parameter	Value	Units
I <sub>D1</sub> @ V <sub>GS</sub> = 10V, T <sub>C</sub> = 25°C	Continuous Drain Current	15	A
I <sub>D2</sub> @ V <sub>GS</sub> = 10V, T <sub>C</sub> = 100°C	Continuous Drain Current	10	
I <sub>DM</sub> @ T <sub>C</sub> = 25°C	Pulsed Drain Current ①	60	
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Maximum Power Dissipation	200	W
	Linear Derating Factor	1.6	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy ②	196	mJ
I <sub>AR</sub>	Avalanche Current ①	15	A
E <sub>AR</sub>	Repetitive Avalanche Energy ①	20	mJ
dv/dt	Peak Diode Recovery ③	14	V/ns
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to + 150	°C
	Lead Temperature	300 (0.063 in. /1.6 mm from case for 10s)	
	Weight	9.3 (Typical)	

For footnotes refer to the page 2.

## Electrical Characteristics @ T<sub>J</sub> = 25°C (Unless Otherwise Specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	800	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	0.87	—	V/°C	Reference to 25°C, I <sub>D</sub> = 1.0mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	0.34	Ω	V <sub>GS</sub> = 10V, I <sub>D2</sub> = 10A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	—	4.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
ΔV <sub>GS(th)</sub> /ΔT <sub>J</sub>	Gate Threshold Voltage Coefficient	—	-7.6	—	mV/°C	
G <sub>fs</sub>	Forward Transconductance	9.3	—	—	S	V <sub>DS</sub> = 15V, I <sub>D2</sub> = 10A ④
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	—	—	10	μA	V <sub>DS</sub> = 800V, V <sub>GS</sub> = 0V
		—	—	25		V <sub>DS</sub> = 800V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
I <sub>GSS</sub>	Gate-to-Source Leakage Forward	—	—	100	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Leakage Reverse	—	—	-100		V <sub>GS</sub> = -20V
Q <sub>G</sub>	Total Gate Charge	—	—	135	nC	I <sub>D1</sub> = 15A
Q <sub>GS</sub>	Gate-to-Source Charge	—	—	20		V <sub>DS</sub> = 400V
Q <sub>GD</sub>	Gate-to-Drain ('Miller') Charge	—	—	60		V <sub>GS</sub> = 10V
t <sub>d(on)</sub>	Turn-On Delay Time	—	—	18	ns	V <sub>DD</sub> = 400V
t <sub>r</sub>	Rise Time	—	—	26		I <sub>D1</sub> = 15A
t <sub>d(off)</sub>	Turn-Off Delay Time	—	—	83		R <sub>G</sub> = 2.4Ω
t <sub>f</sub>	Fall Time	—	—	23		V <sub>GS</sub> = 10V
L <sub>S</sub> + L <sub>D</sub>	Total Inductance	—	6.8	—	nH	Measured from Drain lead (6mm / 0.25 in from package) to Source lead (6mm/ 0.25 in from package)
C <sub>i,ss</sub>	Input Capacitance	—	2300	—	pF	V <sub>GS</sub> = 0V
C <sub>o,ss</sub>	Output Capacitance	—	100	—		V <sub>DS</sub> = 100V
C <sub>r,ss</sub>	Reverse Transfer Capacitance	—	3.3	—		f = 1.0MHz
R <sub>G</sub>	Gate Resistance	—	1.0	—		Ω

## Source-Drain Diode Ratings and Characteristics

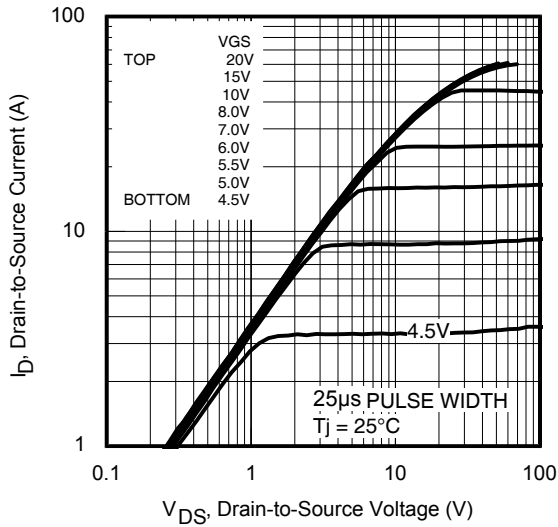
Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	15	A	
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	60		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.2	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 15A, V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	—	990	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 15A, V <sub>DD</sub> ≤ 50V
Q <sub>rr</sub>	Reverse Recovery Charge	—	—	24	μC	di/dt = 100A/μs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

## Thermal Resistance

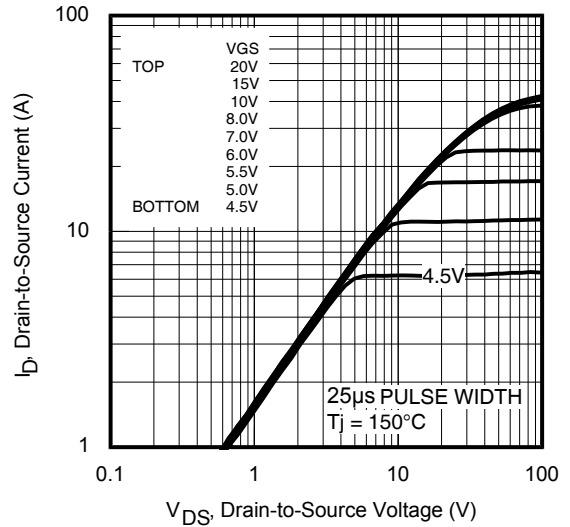
Symbol	Parameter	Min.	Typ.	Max.	Units
R <sub>θJC</sub>	Junction-to-Case	—	—	0.63	°C/W
R <sub>θJA</sub>	Junction-to-Ambient (Typical Socket Mount)	—	—	48	

### Footnotes:

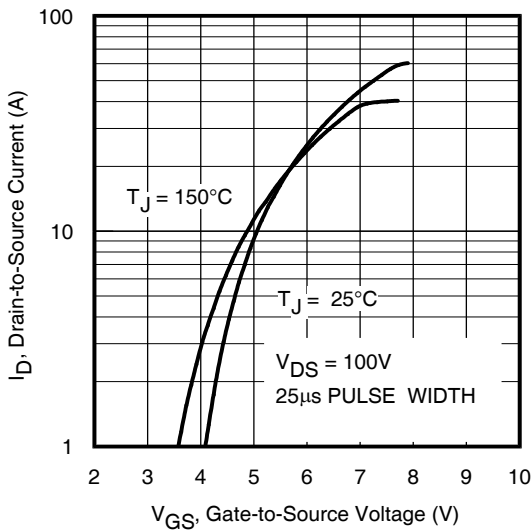
- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- ② V<sub>DD</sub> = 150V, starting T<sub>J</sub> = 25°C, L = 1.7mH, Peak I<sub>L</sub> = 15A, R<sub>G</sub> = 25Ω, V<sub>GS</sub> = 20V.
- ③ I<sub>SD</sub> ≤ 15A, di/dt ≤ 2060A/μs, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>, T<sub>J</sub> ≤ 150°C.
- ④ Pulse width ≤ 300 μs; Duty Cycle ≤ 2%



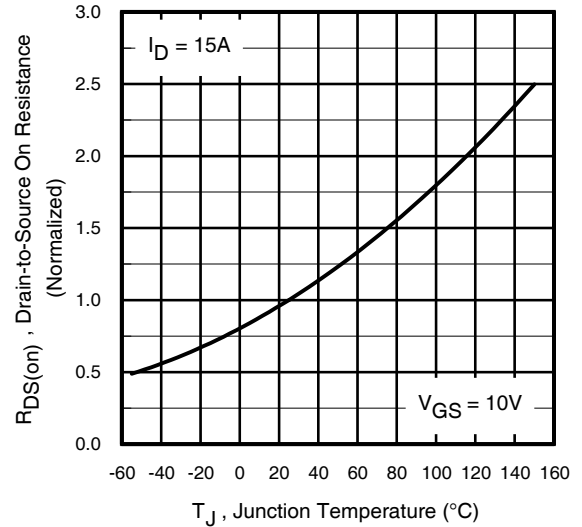
**Fig 1.** Typical Output Characteristics



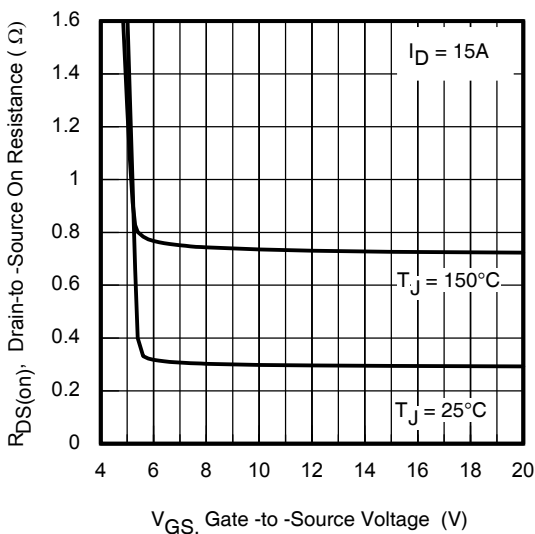
**Fig 2.** Typical Output Characteristics



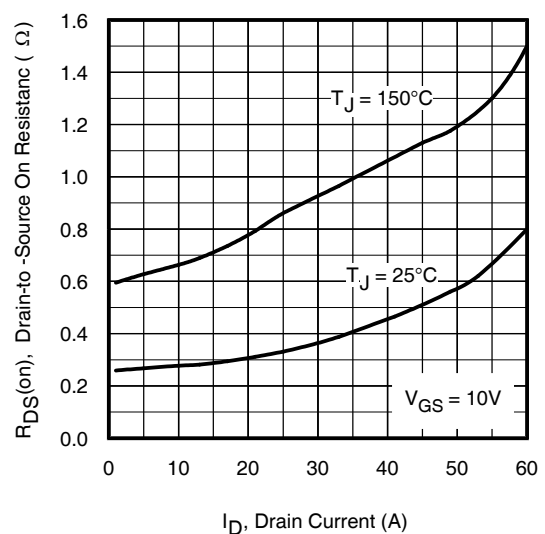
**Fig 3.** Typical Transfer Characteristics



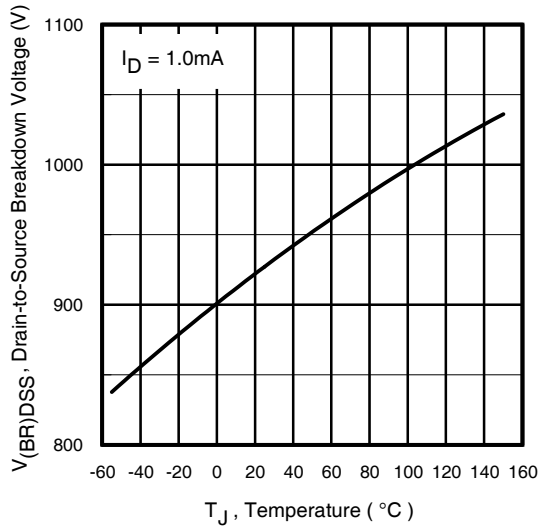
**Fig 4.** Normalized On-Resistance Vs. Temperature



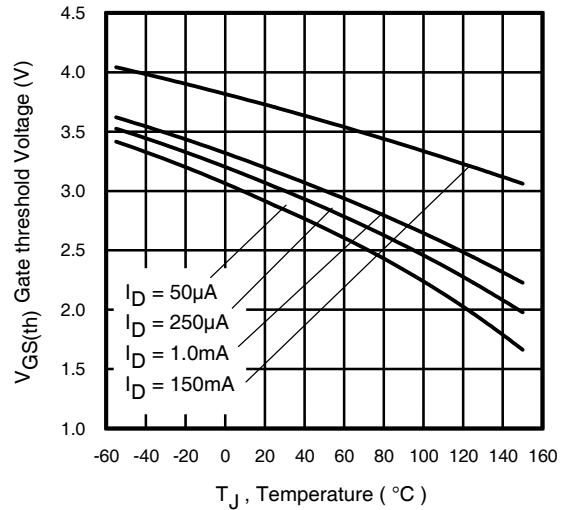
**Fig 5.** Typical On-Resistance Vs Gate Voltage



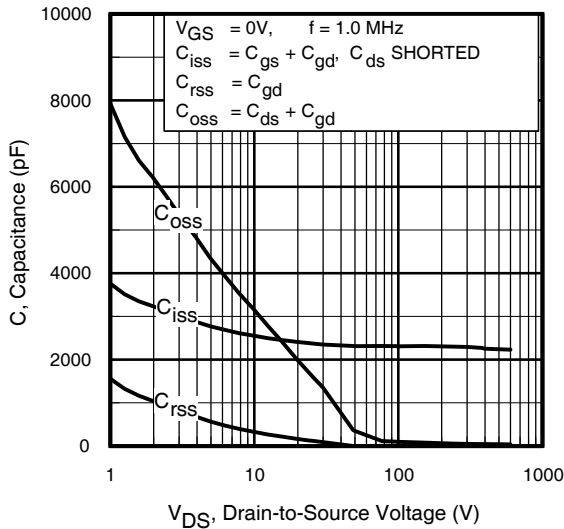
**Fig 6.** Typical On-Resistance Vs Drain Current



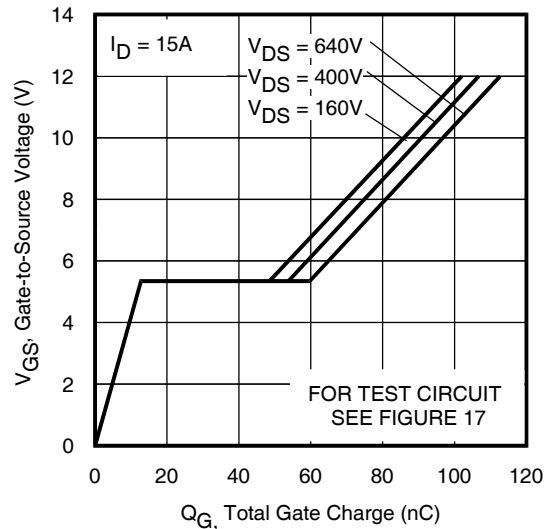
**Fig 7.** Typical Drain-to-Source Breakdown Voltage Vs Temperature



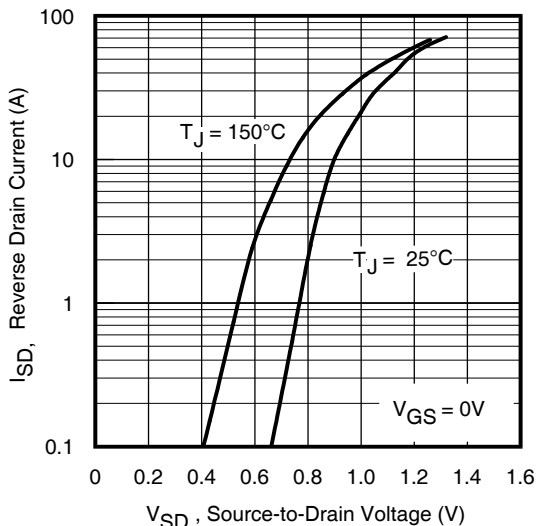
**Fig 8.** Typical Threshold Voltage Vs Temperature



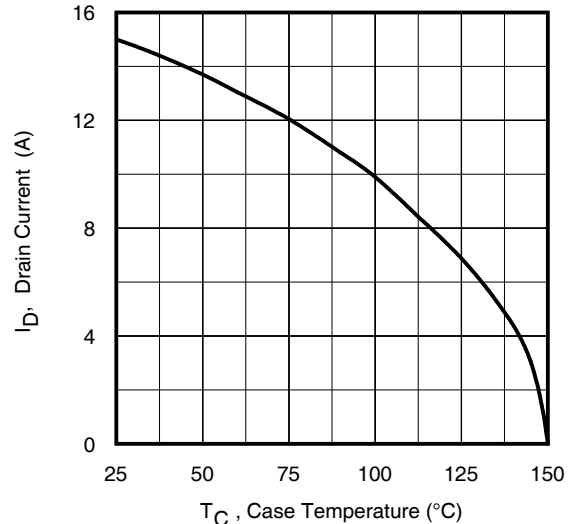
**Fig 9.** Typical Capacitance Vs. Drain-to-Source Voltage



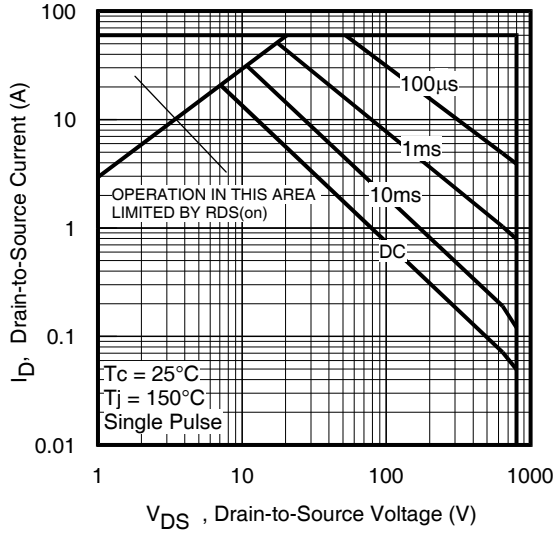
**Fig 10.** Typical Gate Charge Vs. Gate-to-Source Voltage



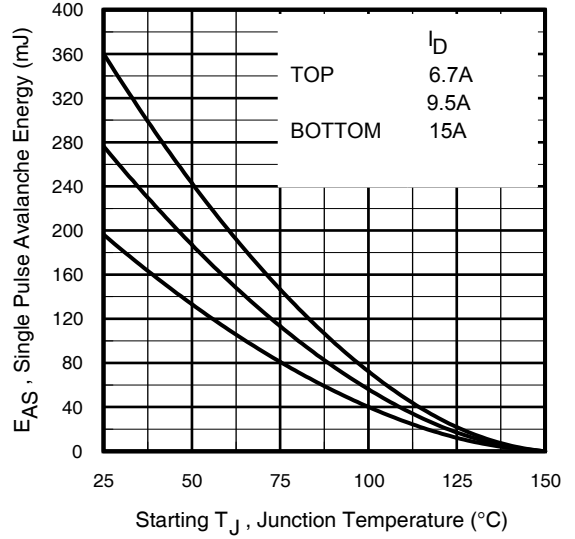
**Fig 11.** Typical Source-Drain Diode Forward Voltage



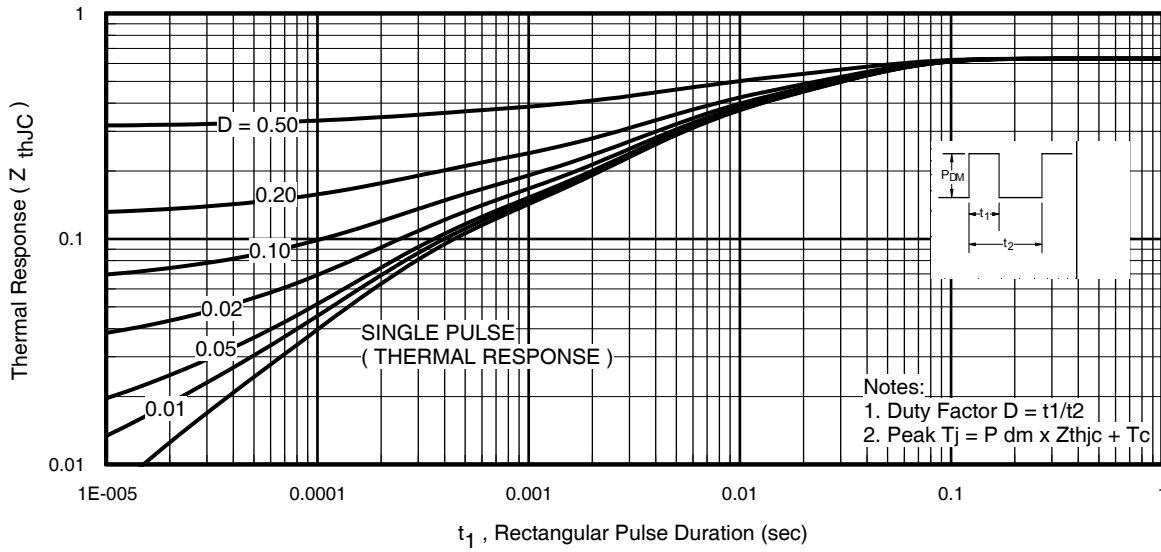
**Fig 12.** Maximum Drain Current Vs. Case Temperature



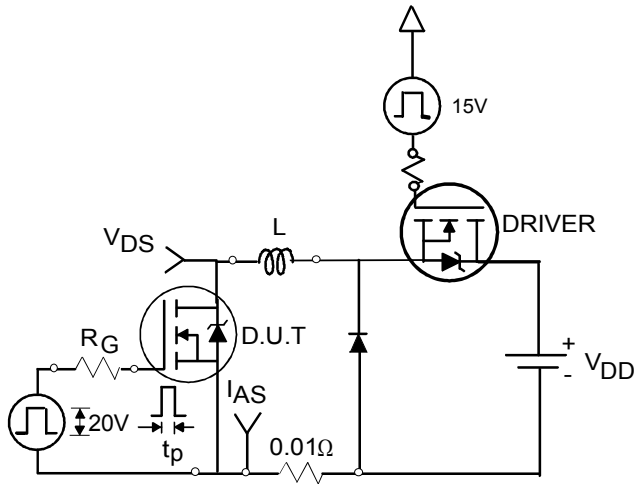
**Fig 13.** Maximum Safe Operating Area



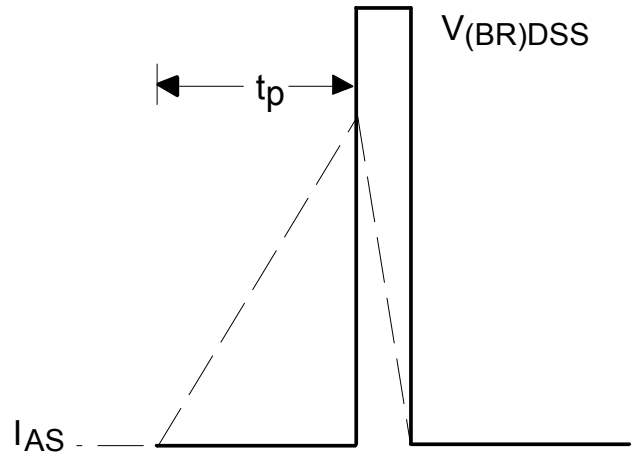
**Fig 14.** Maximum Avalanche Energy Vs. Drain Current



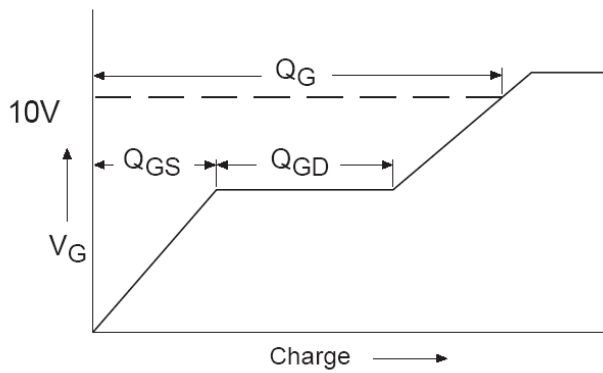
**Fig 15.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



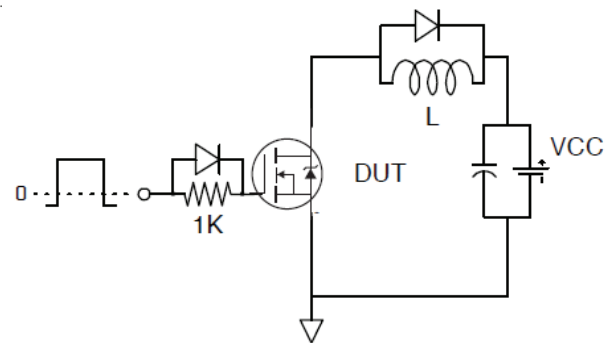
**Fig 16a.** Unclamped Inductive Test Circuit



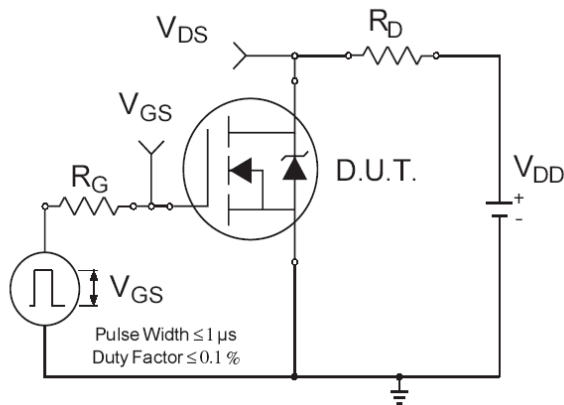
**Fig 16b.** Unclamped Inductive Waveforms



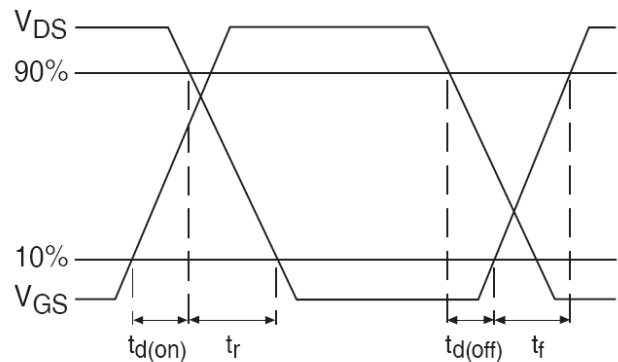
**Fig 17a.** Gate Charge Waveform



**Fig 17b.** Gate Charge Test Circuit

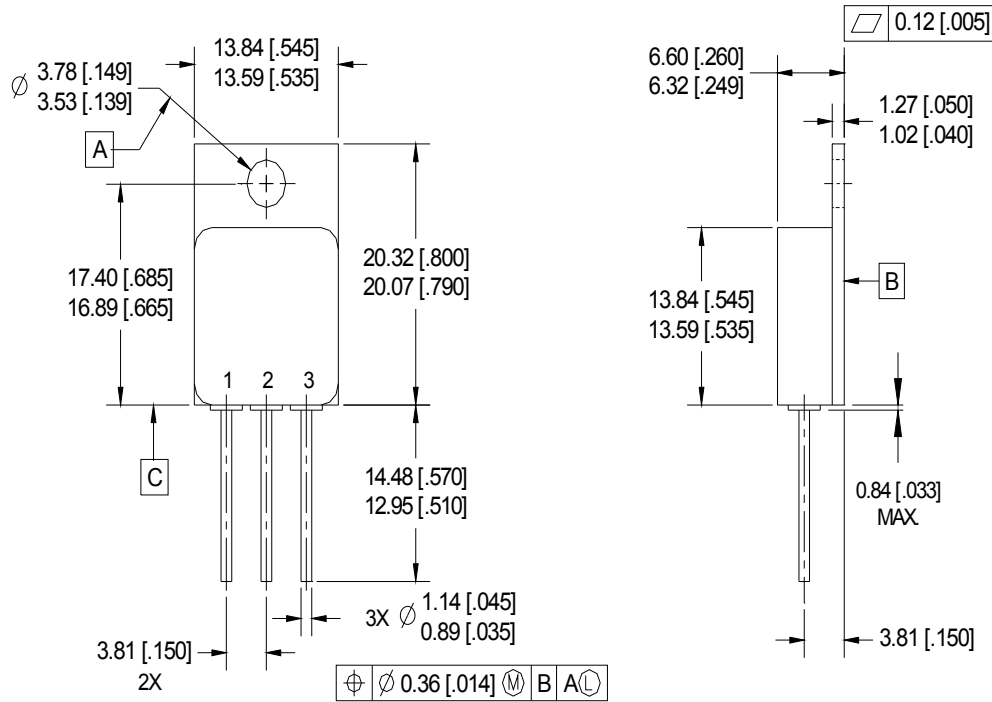


**Fig 18a.** Switching Time Test Circuit



**Fig 18b.** Switching Time Waveforms

**Case Outline and Dimensions - Low-Ohmic TO-254AA**



**NOTES:**

1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. CONTROLLING DIMENSION: INCH.
4. CONFORMS TO JEDEC OUTLINE TO-254AA.

**PIN ASSIGNMENTS**

- 1 = DRAIN
- 2 = SOURCE
- 3 = GATE

**BERYLLIA WARNING PER MIL-PRF-19500**

Package containing beryllia shall not be ground, sandblasted, machined, or have other operations performed on them which will produce beryllia or beryllium dust. Furthermore, beryllium oxide packages shall not be placed in acids that will produce fumes containing beryllium.

### **IMPORTANT NOTICE**

The information given in this document shall be in no event regarded as guarantee of conditions or characteristic. The data contained herein is a characterization of the component based on internal standards and is intended to demonstrate and provide guidance for typical part performance. It will require further evaluation, qualification and analysis to determine suitability in the application environment to confirm compliance to your system requirements.

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